TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74AC174P,TC74AC174F,TC74AC174FN,TC74AC174FT

#### Hex D-Type Flip Flop with Clear

The TC74AC174 is an advanced high speed CMOS HEX D-TYPE FLIP FLOP fabricated with silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

Information signals applied to D inputs are transferred to the Q output on the positive going edge of the clock pulse.

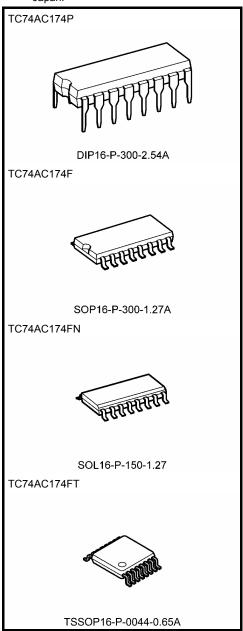
When the  $\overline{\text{CLR}}$  input is held low, the Q output are in the low logic level independent of the other inputs.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### **Features**

- High speed:  $f_{max} = 180 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 8 \mu A$  (max) at  $T_a = 25$ °C
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (min)
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 24$  mA (min) Capability of driving 50  $\Omega$  transmission lines.
- Balanced propagation delays: t<sub>pLH</sub> ≃ t<sub>pHL</sub>
- Wide operating voltage range:  $V_{CC \text{ (opr)}} = 2 \text{ to } 5.5 \text{ V}$
- Pin and function compatible with 74F174

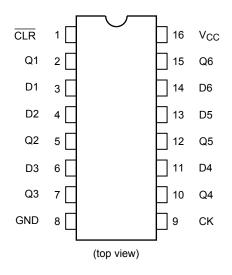
Note: xxxFN (JEDEC SOP) is not available in Japan.



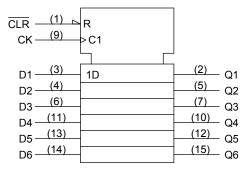
Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.) SOL16-P-150-1.27 : 0.13 g (typ.) TSSOP16-P-0044-0.65A : 0.06 g (typ.)

# **Pin Assignment**



# **IEC Logic Symbol**

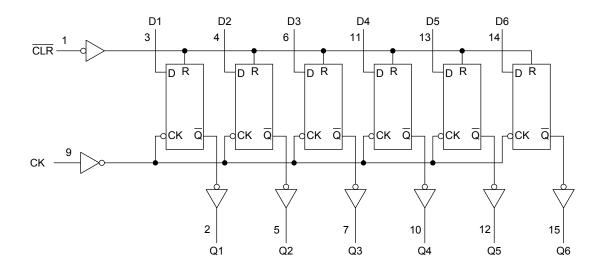


# **Truth Table**

	Inputs		Output	Function		
CLR	D	CK	Q	i unction		
L	Х	Х	L	Clear		
Н	L		L	_		
Н	Н		Н	_		
Н	Х	$\neg$	Qn	No Change		

X: Don't care

### **System Diagram**





#### **Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	−0.5 to 7.0	V
DC input voltage	V <sub>IN</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
DC output voltage	V <sub>OUT</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	±20	mA
Output diode current	lok	±50	mA
DC output current	lout	±50	mA
DC V <sub>CC</sub> /ground current	Icc	±150	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP/TSSOP)	mW
Storage temperature	T <sub>stg</sub>	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to 65°C. From Ta = 65 to 85°C a derating factor of -10 mW/°C should be applied up to 300 mW.

### **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	2.0 to 5.5	V	
Input voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	V	
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	V	
Operating temperature	T <sub>opr</sub>	−40 to 85	°C	
Input rise and fall time	dt/dV	0 to 100 (V <sub>CC</sub> = 3.3 ± 0.3 V)	ns/V	
input rise and fail time	αναν	0 to 20 (V <sub>CC</sub> = 5 ± 0.5 V)	115/ V	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

3



#### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics	Symbol Test Conditio		Test Condition			Ta = 25°C			Ta = −40 to 85°C		Unit	
Characteristics	Cymbol	rest condition		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Onne		
				2.0	1.50	_	_	1.50	_			
High-level input voltage	V <sub>IH</sub>		_		3.0	2.10	_	_	2.10	_	V	
Ğ				5.5	3.85	_	-	3.85	-			
					2.0	_	_	0.50	_	0.50		
Low-level input voltage	$V_{IL}$		_		3.0	_	_	0.90	_	0.90	V	
Ţ.					5.5	-	_	1.65	-	1.65		
	V <sub>ОН</sub>		I <sub>OH</sub> = -50 μA		2.0	1.9	2.0	_	1.9	_		
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>			3.0	2.9	3.0	_	2.9	_		
High-level output					4.5	4.4	4.5	-	4.4	-		
voltage			$I_{OH} = -4 \text{ mA}$		3.0	2.58	_	_	2.48	_	ľ	
			I <sub>OH</sub> = −24 mA		4.5	3.94	_	_	3.80	_		
			I <sub>OH</sub> = -75 mA	(Note)	5.5	-	_	-	3.85	-		
	V <sub>OL</sub>	VIN = VIH or VIL			2.0	_	0.0	0.1	_	0.1		
			I <sub>OL</sub> = 50 μA		3.0	_	0.0	0.1	_	0.1		
Low-level output					4.5	_	0.0	0.1	_	0.1	V	
voltage			I <sub>OL</sub> = 12 mA		3.0	_	_	0.36	_	0.44	V	
			I <sub>OL</sub> = 24 mA		4.5	_	_	0.36	_	0.44		
			I <sub>OL</sub> = 75 mA	(Note)	5.5	_	_	_	_	1.65		
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	±0.1	_	±1.0	μΑ		
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	8.0	_	80.0	μА		

Note: This spec indicates the capability of driving 50  $\Omega$  transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

### Timing Requirements (input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition		Ta = 25°C	Ta = -40 to 85°C	Unit
			V <sub>CC</sub> (V)	Limit	Limit	
Minimum pulse width	t <sub>w (L)</sub>		$3.3 \pm 0.3$	7.0	7.0	ns
(CK)	t <sub>w (H)</sub>	_	$5.0 \pm 0.5$	5.0	5.0	
Minimum pulse width	4		$3.3 \pm 0.3$	7.0	7.0	ns
( CLR )	t <sub>w (L)</sub>	_	$5.0 \pm 0.5$	5.0	5.0	
Minimum act un time	4		$3.3 \pm 0.3$	7.0	7.0	ns
Minimum set-up time	t <sub>S</sub>	_	$5.0 \pm 0.5$	4.0	4.0	
Minimum hold time	4.		$3.3 \pm 0.3$	1.0	1.0	20
Minimum noid time	t <sub>h</sub>	_	$5.0 \pm 0.5$	1.0	1.0	ns
Minimum removal time	4		$3.3 \pm 0.3$	6.0	6.0	
(CLR)	t <sub>rem</sub>	_	$5.0 \pm 0.5$	3.5	3.5	ns



#### AC Characteristics ( $C_L$ = 50 pF, $R_L$ = 500 $\Omega$ , input: $t_r$ = $t_f$ = 3 ns)

Characteristics	Symbol	Test Condition	ndition		Ta = 25°C			Ta = -40 to 85°C	
	-,		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit
Propagation delay time (CK-Q)	t <sub>pLH</sub>	_	$3.3 \pm 0.3$ $5.0 \pm 0.5$	_ _	8.5 6.7	14.4 9.6	1.0 1.0	16.6 11.0	ns
Propagation delay time	t <sub>pHL</sub>	_	$3.3 \pm 0.3$ $5.0 \pm 0.5$	_	8.2 6.3	13.9 9.0	1.0 1.0	16.0 10.4	ns
Maximum clock frequency	f <sub>max</sub>	_	$3.3 \pm 0.3$ $5.0 \pm 0.5$	60 90	110 150	_	60 90		MHz
Input capacitance	C <sub>IN</sub>	_		_	5	10	_	10	pF
Power dissipation capacitance	C <sub>PD</sub>		(Note)	_	74	_	_	_	pF

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

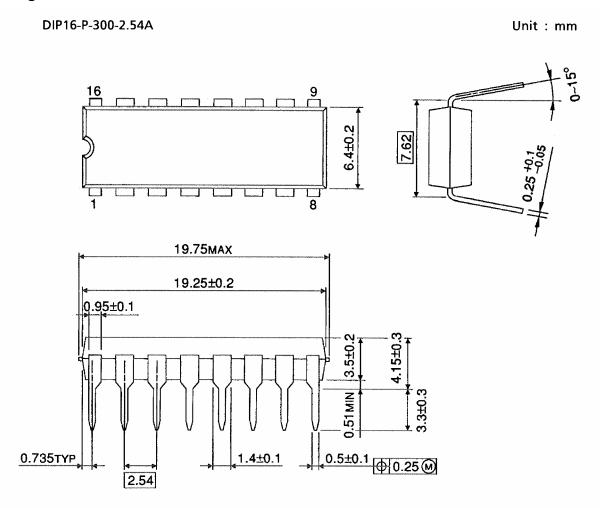
Average operating current can be obtained by the equation:

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/6 (per F/F)$$

And the total  $C_{\mbox{\scriptsize PD}}$  when n pcs of flip flop operate can be gained by the following equation:

5

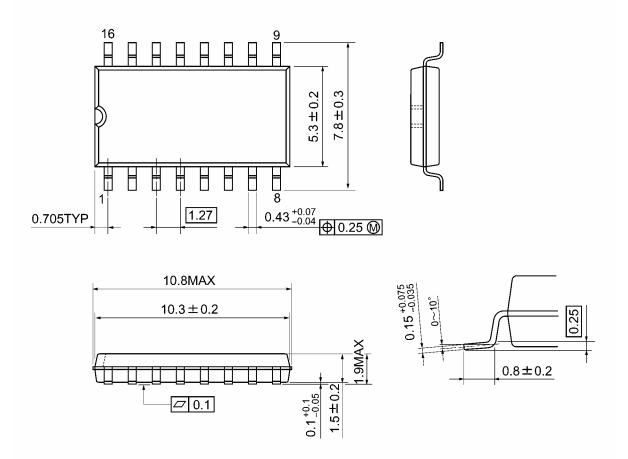
# **Package Dimensions**



Weight: 1.00 g (typ.)

# **Package Dimensions**

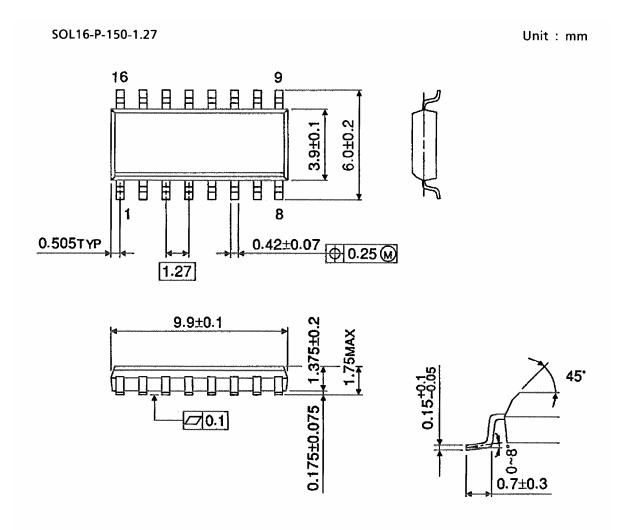
SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)



# **Package Dimensions (Note)**



8

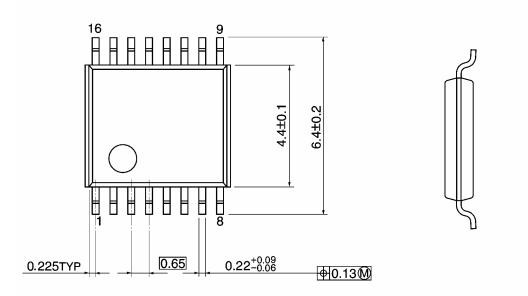
Note: This package is not available in Japan.

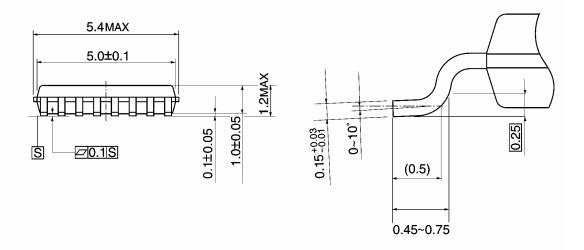
Weight: 0.13 g (typ.)

# **Package Dimensions**

**TOSHIBA** 

TSSOP16-P-0044-0.65A Unit: mm





Weight: 0.06 g (typ.)

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20070701-EN GENERAL

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